

**FROMMER LAWRENCE & HAUG LLP**

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June 21, 2000

Assistant Commissioner for Patents  
Washington, D.C. 20231

Re: U.S. Patent Application  
Applicants: Besma KRAIEM, Janos ENDERLEIN  
Our Ref.: 450117-02628

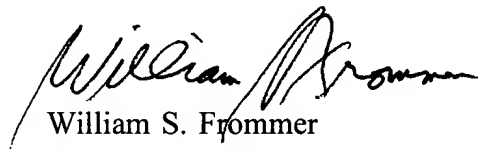
Dear Sir:

Enclosed are papers constituting the above patent application which is being filed under 37 C.F.R. 1.53 without a signed Declaration. Please accord a filing date and a serial number to such application and inform the undersigned thereof so that a signed Declaration and the surcharge required by 37 C.F.R. 1.16(e) may be duly filed.

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Respectfully,



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Enclosures